

MT4805

Dual P-Channel Enhancement Mode Field Effect Transistor

-30V, -8A, 22mΩ

Features

- $R_{DS(on)} = 22\text{ m}\Omega$ at $V_{GS} = -10\text{V}$, $I_D = -8\text{A}$
- Fast Switching Speed
- Low Gate Charge
- High Performance Trench Technology for Extr emely Low $R_{DS(on)}$
- High Power and Current Handling Capability
- RoHS Compliant

General Description

This P-Channel MOSFET is produced using MOS-TECH Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Applications

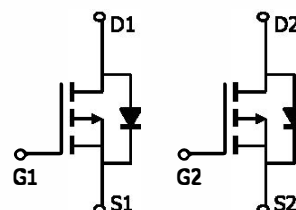
- DC-DC primary bridge
- DC-DC Synchronous rectification
- Hot swap



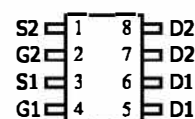
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Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



SO-8

MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Absolute Maximum Ratings T _A =25°C unless otherwise noted					
Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		V _{DS}	-30	V	
Gate-Source Voltage		V _{GS}	±20	V	
Continuous Drain Current ^A	T _A =25°C	I _D	-8.0	A	
	T _A =70°C		-6.2		
Pulsed Drain Current ^E		I _{DM}	-30		
Power Dissipation ^A	T _A =25°C	P _D	2	W	
	T _A =70°C		1.28		
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150	°C	

Thermal Characteristics					
Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$t \leq 10\text{s}$	$R_{\theta JA}$	48	62.5	$^\circ\text{C/W}$
Maximum Junction-to-Ambient ^A	Steady-State		74	110	$^\circ\text{C/W}$
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	35	40	$^\circ\text{C/W}$

Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-1.0	-1.8	-2.5	V
$I_{D(ON)}$	On state drain current	$V_{GS}=-10\text{V}$, $V_{DS}=-5\text{V}$	-30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$, $I_D=-8\text{A}$ $T_J=125^{\circ}\text{C}$		22 27	25 33	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}$, $I_D=-5.6\text{A}$		32	36	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-7.1\text{A}$		19.6		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-4.2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-15\text{V}$, $f=1\text{MHz}$		1573		pF
C_{oss}	Output Capacitance			319		pF
C_{rss}	Reverse Transfer Capacitance			211		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		6.7		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge (10V)	$V_{GS}=-10\text{V}$, $V_{DS}=-15\text{V}$, $I_D=-7.1\text{A}$		30.9		nC
$Q_g(4.5\text{V})$	Total Gate Charge (4.5V)			16.1		nC
Q_{gs}	Gate Source Charge			8		nC
Q_{gd}	Gate Drain Charge			4.4		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=-10\text{V}$, $V_{DS}=-15\text{V}$, $R_L=2.2\Omega$, $R_{GEN}=3\Omega$		9.5		ns
t_r	Turn-On Rise Time			8		ns
$t_{D(off)}$	Turn-Off DelayTime			44.2		ns
t_f	Turn-Off Fall Time			22.2		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-7.1\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		25.5		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-7.1\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		14.7		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $\leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D: The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The SOA curve provides a single pulse rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

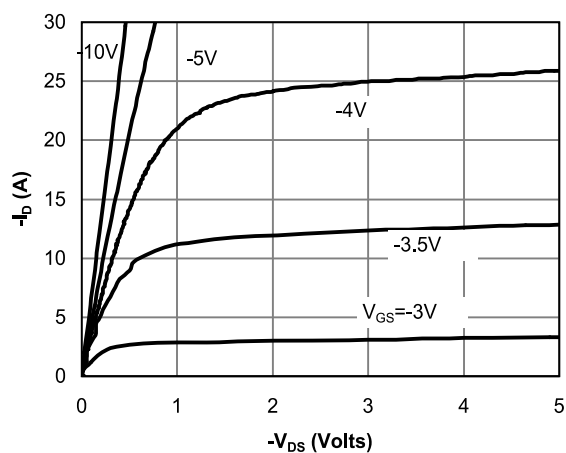


Fig 1: On-Region Characteristics

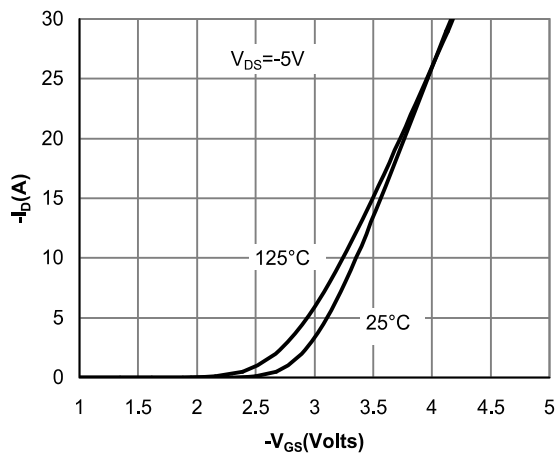


Figure 2: Transfer Characteristics

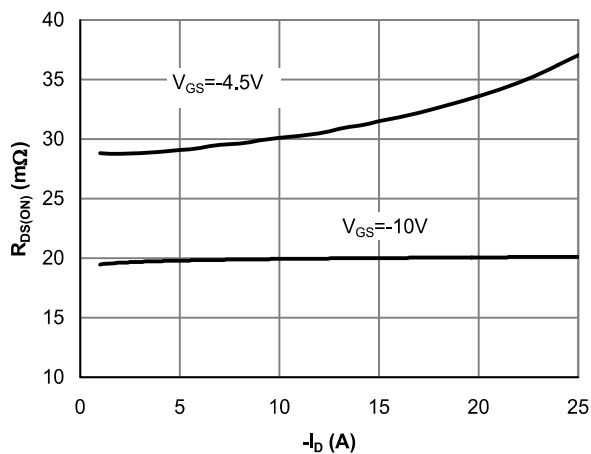


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

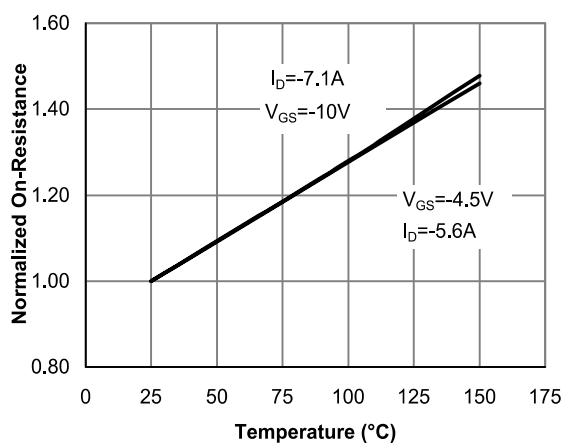


Figure 4: On-Resistance vs. Junction Temperature

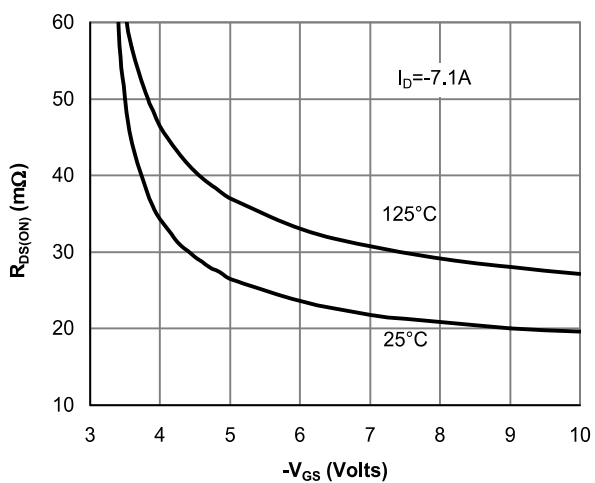


Figure 5: On-Resistance vs. Gate-Source Voltage

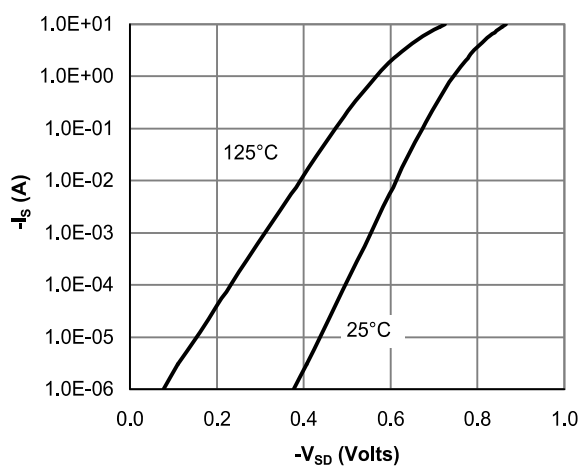


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

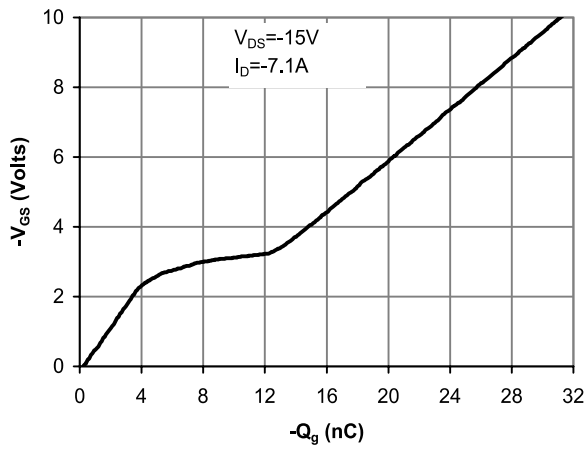


Figure 7: Gate-Charge Characteristics

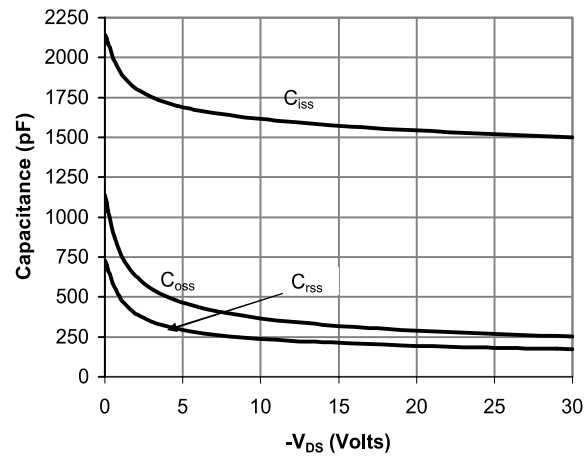


Figure 8: Capacitance Characteristics

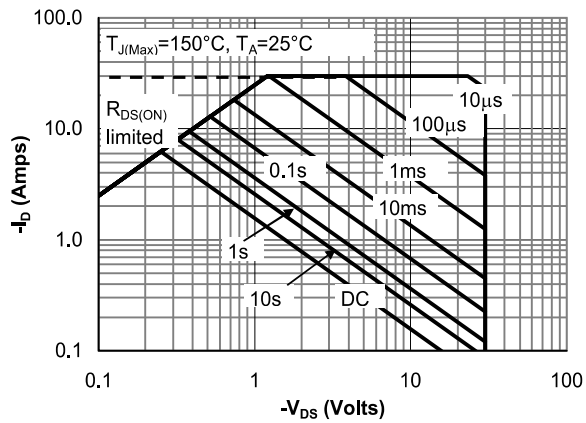


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

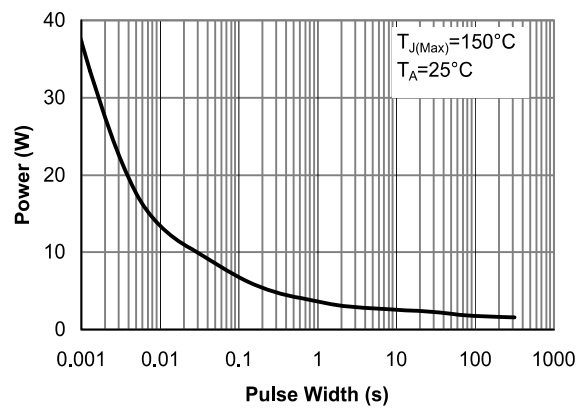


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

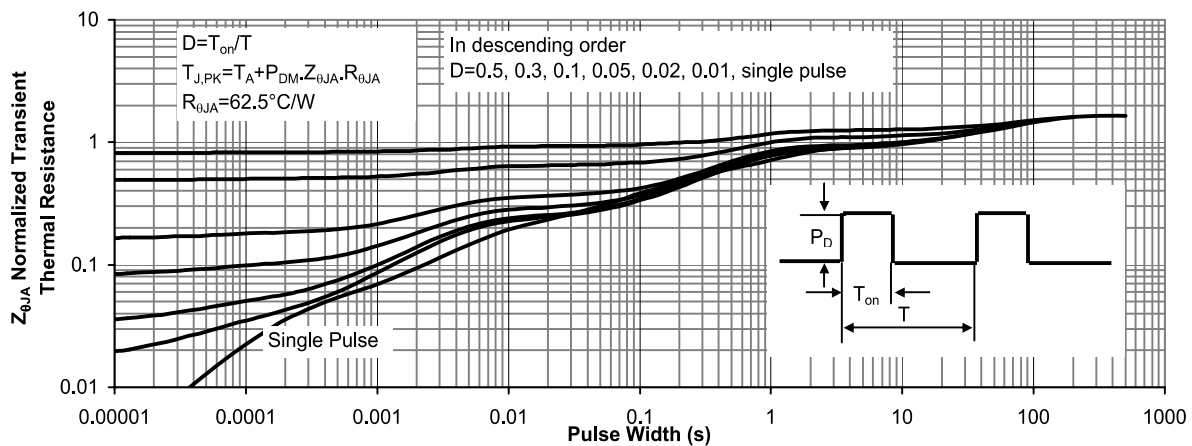


Figure 11: Normalized Maximum Transient Thermal Impedance

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